

## FEATURES

- Originative New Design
- 100% EAS Test
- Rugged Gate Oxide Technology
- Extremely Low Intrinsic Capacitances
- Remarkable Switching Characteristics
- Unequalled Gate Charge : 30.5 nC (Typ.)
- Extended Safe Operating Area
- Lower  $R_{DS(on)}$  : 1.9Ω (Typ.) @ $V_{GS}=10V$
- Halogen Free

## APPLICATION

- High current, High speed switching
- Suitable for power supplies, adaptors and PFC
- SMPS (Switched Mode Power Supplies)

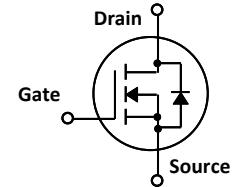
# PFI6N90EG

## 900V N-Channel MOSFET

**$BV_{DSS} = 900\text{ V}$**

**$R_{DS(on)} = 1.9\text{ }\Omega$**

**$I_D = 5.7\text{ A}$**



**TO-262-3L**



1.Gate 2. Drain 3. Source

## Absolute Maximum Ratings $T_c=25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Value	Units
$V_{DSS}$	Drain-Source Voltage	900	V
$I_D$	Drain Current – Continuous ( $T_c = 25^\circ\text{C}$ )	5.7	A
	Drain Current – Continuous ( $T_c = 100^\circ\text{C}$ )	3.6	A
$I_{DM}$	Drain Current – Pulsed (Note 1)	23.0	A
$V_{GS}$	Gate-Source Voltage	$\pm 30$	V
$E_{AS}$	Single Pulsed Avalanche Energy (Note 2)	630	mJ
$I_{AR}$	Avalanche Current (Note 1)	5.7	A
$E_{AR}$	Repetitive Avalanche Energy (Note 1)	16.7	mJ
$dv/dt$	Peak Diode Recovery $dv/dt$ (Note 3)	4.5	V/ns
$P_D$	Power Dissipation ( $T_c = 25^\circ\text{C}$ )	167	W
	- Derate above $25^\circ\text{C}$	1.3	$^\circ\text{C}/\text{W}$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	$^\circ\text{C}$

\* Drain current limited by maximum junction temperature.

## Thermal Resistance Characteristics

Symbol	Parameter	Maximum	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.75	$^\circ\text{C}/\text{W}$
$R_{\theta JS}$	Thermal Resistance, Junction-to-Sink	0.5	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	

**Electrical Characteristics**  $T_c=25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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**On Characteristics**

$V_{GS}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu\text{A}$	2.5	--	4.5	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}$ , $I_D = 3.0 \text{ A}$	--	1.9	2.3	$\Omega$

**Off Characteristics**

$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}$ , $I_D = 250 \mu\text{A}$	900	--	--	V
$\Delta BV_{DSS} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$ , Referenced to $25^\circ\text{C}$	--	0.5	--	$\text{V}/^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 900 \text{ V}$ , $V_{GS} = 0 \text{ V}$	--	--	10	$\mu\text{A}$
		$V_{DS} = 720 \text{ V}$ , $T_C = 125^\circ\text{C}$	--	--	100	$\mu\text{A}$
$I_{GSSF}$	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}$ , $V_{DS} = 0 \text{ V}$	--	--	100	nA
$I_{GSSR}$	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}$ , $V_{DS} = 0 \text{ V}$	--	--	-100	nA

**Dynamic Characteristics**

$C_{iss}$	Input Capacitance	$V_{DS} = 25 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $f = 1.0 \text{ MHz}$	--	1660	2160	pF
$C_{oss}$	Output Capacitance		--	105	135	pF
$C_{rss}$	Reverse Transfer Capacitance		--	16	22	pF

**Switching Characteristics**

$t_{d(on)}$	Turn-On Time	$V_{DS} = 450 \text{ V}$ , $I_D = 6.0 \text{ A}$ , $R_G = 25 \Omega$ , $R_L = 75 \Omega$ (Note 4,5)	--	28	55	ns
$t_r$	Turn-On Rise Time		--	22	45	ns
$t_{d(off)}$	Turn-Off Delay Time		--	60	120	ns
$t_f$	Turn-Off Fall Time		--	24	50	ns
$Q_g$	Total Gate Charge	$V_{DS} = 720 \text{ V}$ , $I_D = 6.0 \text{ A}$ , $V_{GS} = 10 \text{ V}$ (Note 4,5)	--	30.5	45	nC
$Q_{gs}$	Gate-Source Charge		--	10	--	nC
$Q_{gd}$	Gate-Drain Charge		--	7	--	nC

**Source-Drain Diode Maximum Ratings and Characteristics**

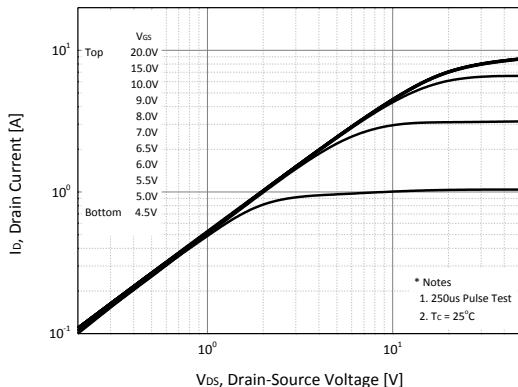
$I_S$	Continuous Source-Drain Diode Forward Current	--	--	5.7	A	
$I_{SM}$	Pulsed Source-Drain Diode Forward Current	--	--	23.0		
$V_{SD}$	Source-Drain Diode Forward Voltage	$I_S = 6.0 \text{ A}$ , $V_{GS} = 0 \text{ V}$	--	--	1.4	V
$trr$	Reverse Recovery Time	$I_S = 6.0 \text{ A}$ , $V_{GS} = 0 \text{ V}$ $di_F/dt = 100 \text{ A/us}$ (Note 4)	--	505	--	ns
$Qrr$	Reverse Recovery Charge		--	5.3	--	uC

**Notes ;**

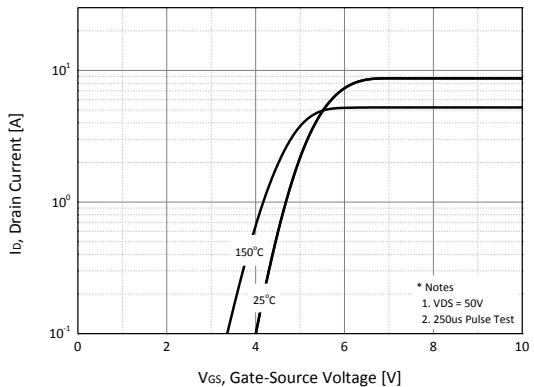
- Repetitive Rating : Pulse width limited by maximum junction temperature
- $L=35\text{mH}$ ,  $I_{AS}=6.0\text{A}$ ,  $V_{DD}=50\text{V}$ ,  $R_G=25\Omega$ , Starting  $T_J=25^\circ\text{C}$
- $I_{SD}\leq 6.0\text{A}$ ,  $di/dt\leq 200\text{A/us}$ ,  $V_{DD}\leq BV_{DSS}$ , Starting  $T_J=25^\circ\text{C}$
- Pulse Test : Pulse Width  $\leq 300\text{us}$ , Duty Cycle  $\leq 2\%$
- Essentially Independent of Operating Temperature

## Typical Characteristics

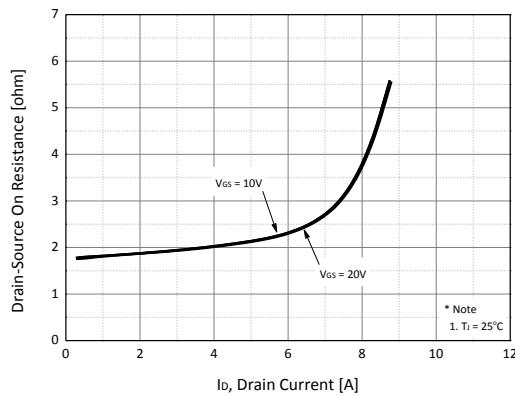
**Fig.1 On Region Characteristics**



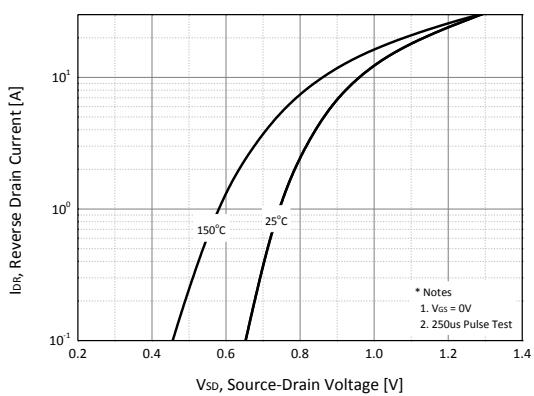
**Fig.2 Transfer Characteristics**



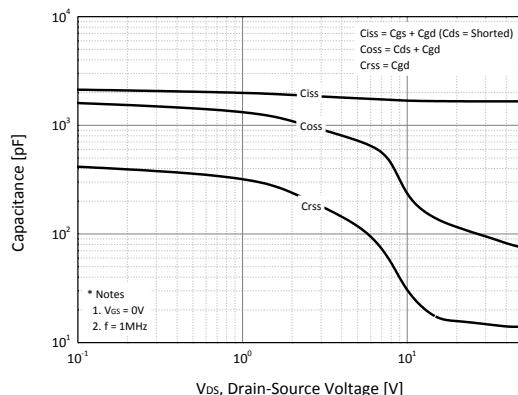
**Fig.3 Static Drain-Source On Resistance**



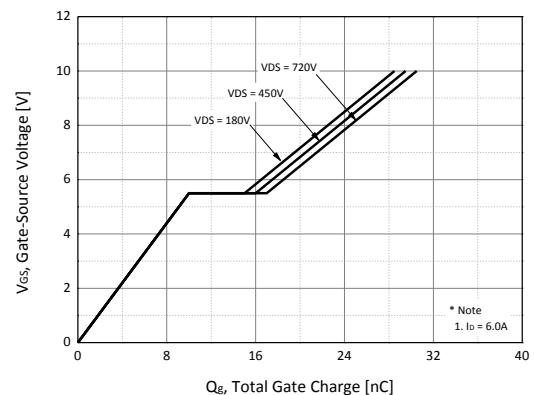
**Fig.4 Body Diode Forward Voltage**



**Fig.5 Capacitance Characteristics**

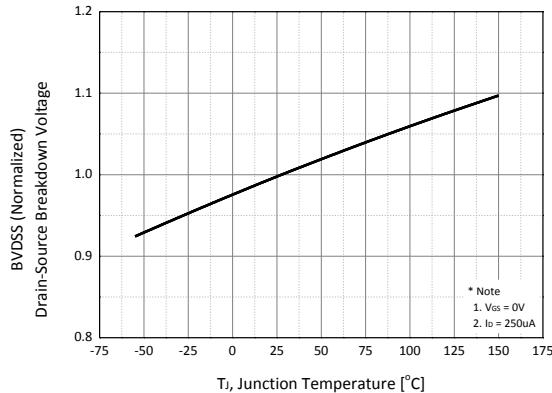


**Fig.6 Gate Charge Characteristics**

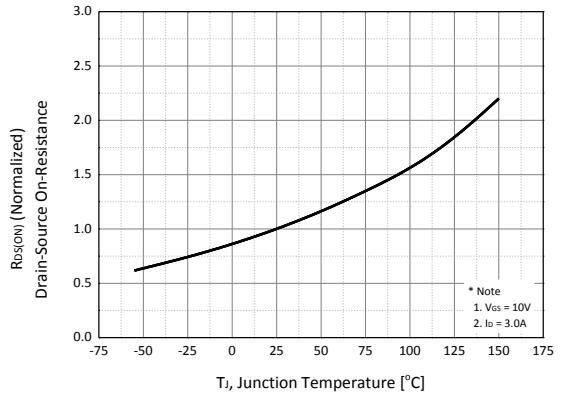


## Typical Characteristics

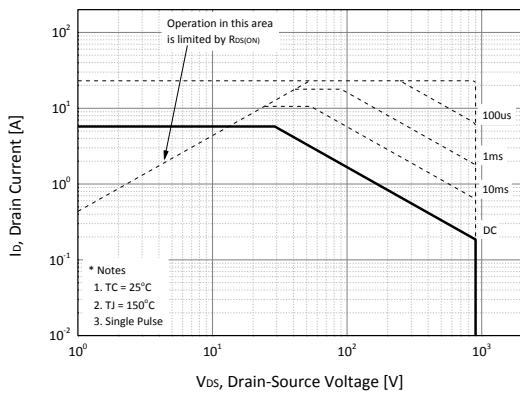
**Fig.7 BV<sub>DSS</sub> Variation vs. Temperature**



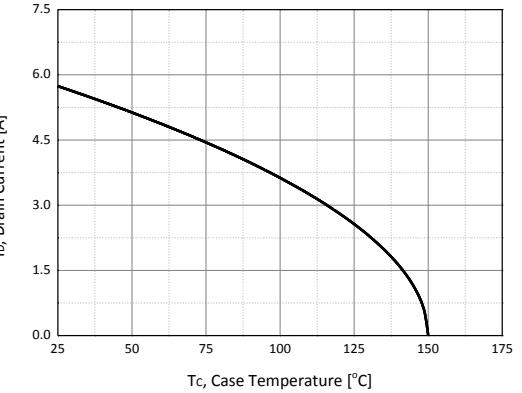
**Fig.8 On-Resistance Variation vs. Temperature**



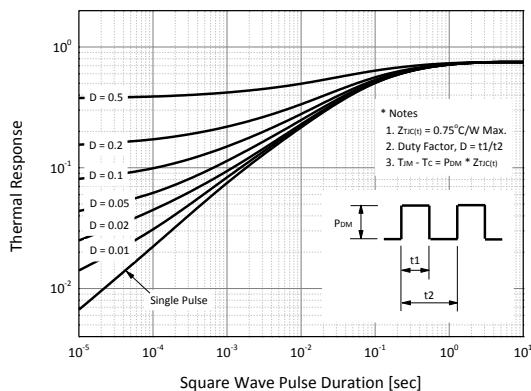
**Fig.9 Safe Operation Area**



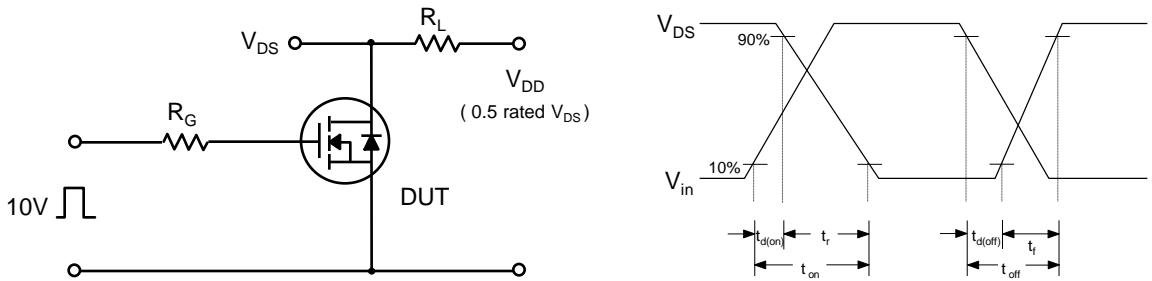
**Fig.10 Maximum I<sub>D</sub> vs. Case Temperature**



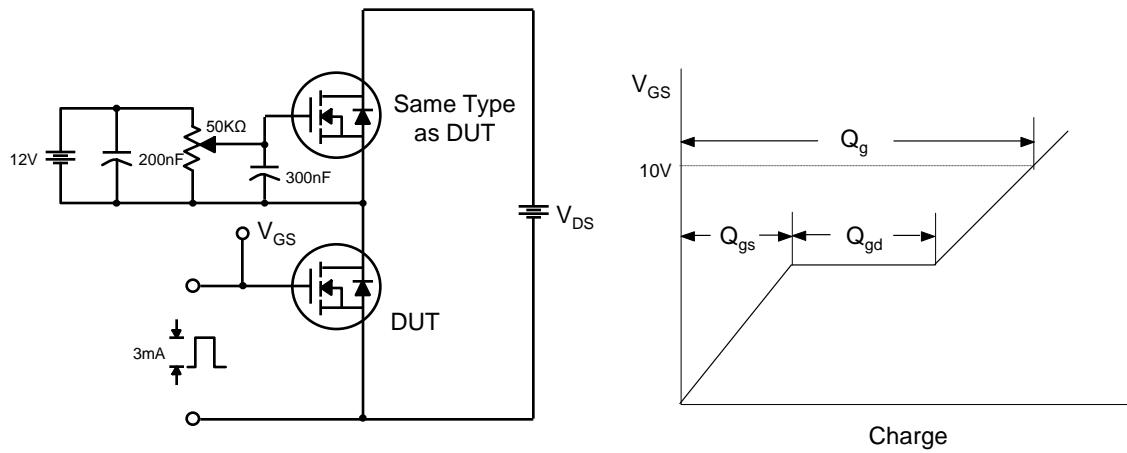
**Fig.11 Transient Thermal Response Curve**



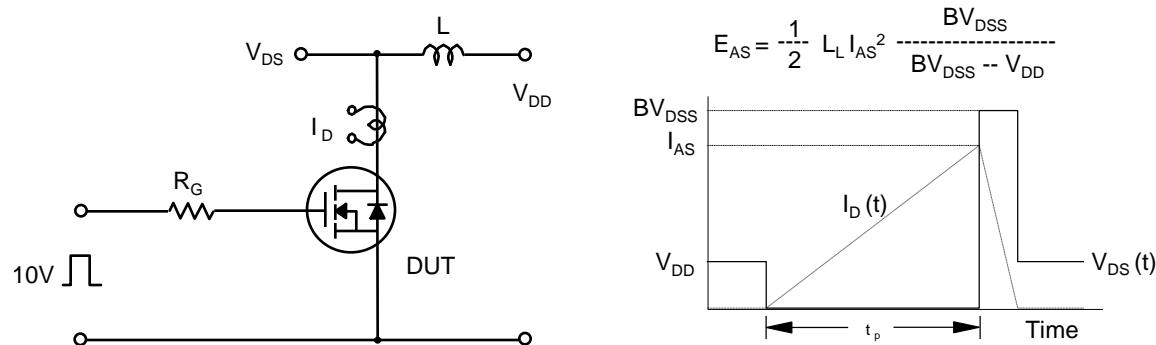
## Characteristics Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms

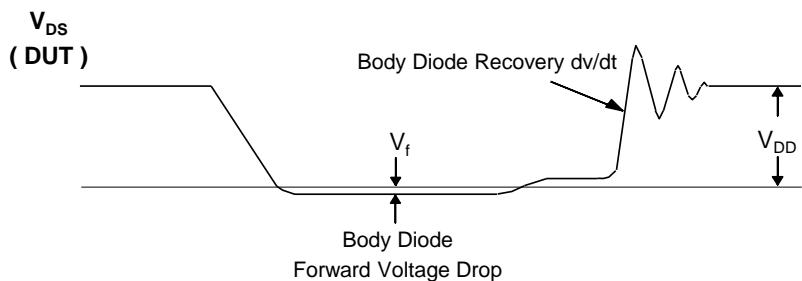
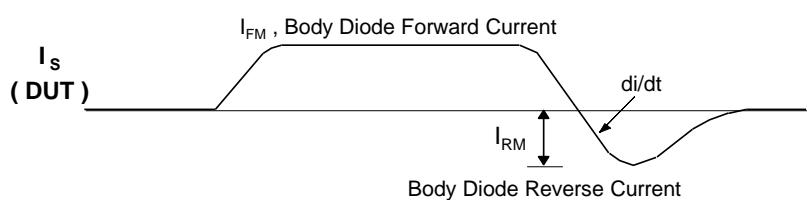
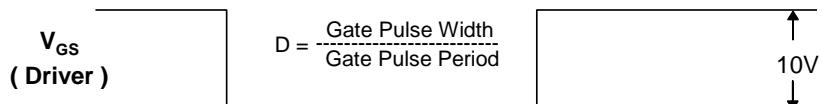
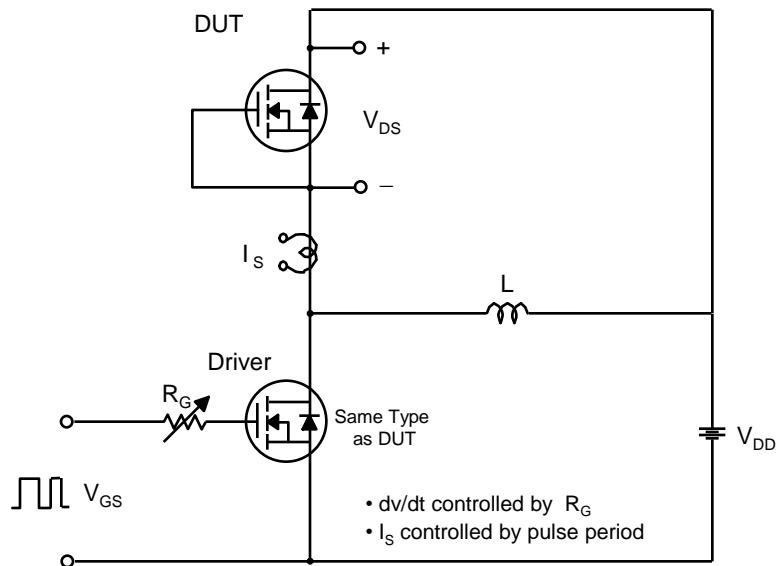


Gate Charge Test Circuit & Waveform



Unclamped Inductive Switching Test Circuit & Waveforms

## Characteristics Test Circuit & Waveform (continued)



**Peak Diode Recovery  $dv/dt$  Test Circuit & Waveforms**

**Package Dimension****TO-262 (I2-PAK)**